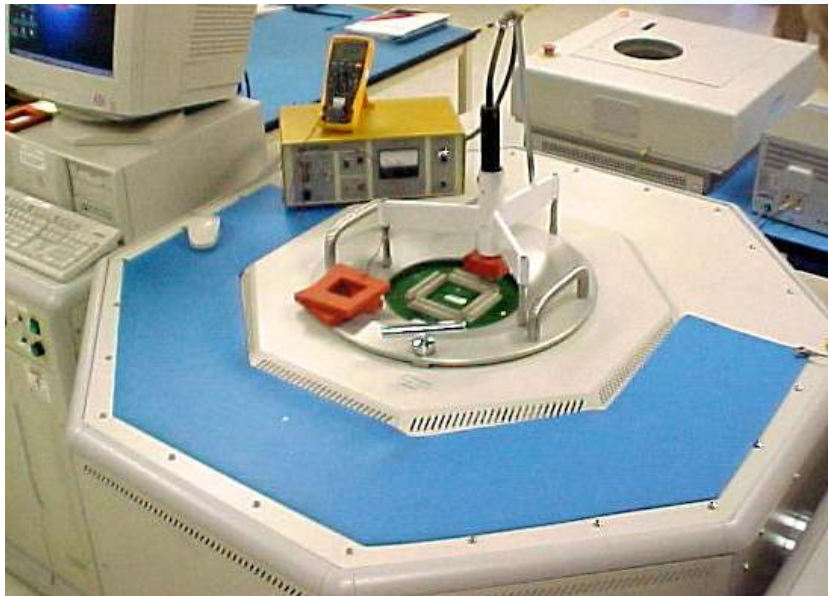


ESD & Latch-Up Test Service

Automated Latch-up Testing:

- Static, Dynamic and Transient Latch-up
- Testing available: CMOS / EIA / JEDEC No. 17 & 78; custom; elevated temperature to 150°C
- Testing up to 1024 pins



ESD Classification Testing:

- Establish ESD sensitivities and failure threshold
- ESD Testing per JEDEC, ESDA, Mil-Std-883, AEC and Lucent standards
- Pass / Fail / Analysis: Graphically monitor leakage changes
- Testing available: Human Body Model (HBM), Machine Model (MM), and Charged Device Model (CDM)
- Testing up to 1024 pins
- Package or Die level test